

Holography from thermal infrared to terahertz in view of applications in metrology and nondestructive testing

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Centre Spatial de Liège

Optics for Space



Center of Excellence for Optics of Cesa

Testing of space payloads in vacuum-thermal chambers





Development of optical space instrumentation











Development of Advanced Technologies

- Vacuum-Cryogeny
- Quality insurance
- Thermal Design
- Signal Processing
- Spaceborne Electronics
- Smart sensors
- Surface processing
- Optical Design
- Optical Metrology
- Non Destructive Testing









Summary

- Some basics of holography
 - Recording-reconstruction
 - Applications
 - Where long wavelengths matter
- Long-wave IR digital holography
 - Applications in aerospace
- THz digital holography
 - FIR
 - Sub-THz

Holography at long wavelength (IR to THz waves)

- Holography: recording of whole wavefield information: amplitude and phase
- No analog hologram recording material
- Numerical recording of hologram with camera sensors: « Digital Holography »
- Digital Holography principle

Step 1: Recording hologram



Digital Holography principle - 2

Step 2: Reconstruction by scalar diffraction theory



$$U(x, y, d) = \mathcal{F}^{-1}\big\{\mathcal{F}\{U(x, y, 0)\}, H\big(f_x, f_y\big)\big\}$$

Rigorous : Angular Spectrum Method (ASM)



Paraxial approximation: distance *d* >> object size

$$H_{Fresnel}(f_x, f_y) \approx exp\left[i\frac{2\pi}{\lambda}d\left(1-\frac{\lambda^2}{2}\left(f_x^2+f_y^2\right)\right)\right]$$

Fresnel lens-less DH reconstruction principle

$$U(x, y, d) = \frac{i}{\lambda d} e^{-i2\pi d/\lambda} \exp\left[-i\frac{\pi}{\lambda d}(x^2 + y^2)\right] \iint I(u, v) U_r(u, v) \exp\left[-i\frac{\pi}{\lambda d}(u^2 + v^2)\right] \exp\left[i\frac{2\pi}{\lambda d}(xu + yv)\right] du dv$$

Digital Holography principle - 3

Reconstruction by Fresnel lensless DH principle

$$U(x, y, d) \div \iint I(u, v) U_r(u, v) \exp\left[-i\frac{\pi}{\lambda d}(u^2 + v^2)\right] \exp\left[i\frac{2\pi}{\lambda d}(xu + yv)\right] du dv$$
$$\mathcal{F}\left\{I(u, v) U_r(u, v) \exp\left[-i\frac{\pi}{\lambda d}(u^2 + v^2)\right]\right\} \qquad \text{"S-FFT"}$$





Resolution: full

Digital Holography principle - 3

Reconstruction by Fresnel lensless DH principle

$$U(x, y, d) \div \iint I(u, v) U_r(u, v) \exp\left[-i\frac{\pi}{\lambda d}(u^2 + v^2)\right] \exp\left[i\frac{2\pi}{\lambda d}(xu + yv)\right] du dv$$
$$\mathcal{F}\left\{I(u, v) U_r(u, v) \exp\left[-i\frac{\pi}{\lambda d}(u^2 + v^2)\right]\right\} \qquad \text{``S-FFT''}$$





Amplitude

 $A_o(x, y, d) = \sqrt{Re^2(U_o(x, y, d)) + Im^2(U_o(x, y, d))}$

Phase

$$\varphi_o(x, y, d) = \tan^{-1} \left[\frac{Im(U_o(x, y, d))}{Re(U_o(x, y, d))} \right]$$

Applications

Imaging

Reflecting objects



Changing reconstruction distance z to best focus at z = d

Interferometry

Record time series of holograms





Reflecting objects

displacements deformations

 $\phi \mod 2\pi$





Transparent objects



Digital Holographic Microscope Quantitative phase imaging

Transparent objects

© Dubois

Refractive index changes



© Desse, Picart



Where long wavelength matters

Object size



Stability of setup

d: reconstruction distance λ : wavelength Δ : pixel size

$$\left[\frac{\lambda}{\Delta}\right]_{10\mu m} \sim 7 \left[\frac{\lambda}{\Delta}\right]_{532nm}$$



Stability criterion during hologram recording: Hologram pattern $\{I(u, v)\}$ cannot move by

a fraction of wavelength, generally $\frac{\lambda}{10}$

Longer λ allow working in perturbed environments

Measurement range in interferometric metrology

wavelength



Measurement range : number of resolvable fringes depends on

Longer λ allow large displacement or deformation measurements

Transmission of object/matter is function of wavelength

Obviously necessary for inspection/phase measurement of transparent objects

- Application in metrology for European Space Agency Cesa
- ESA needs:
 - Full-field deformations of space reflectors in vacuum-thermal testing
 - Large reflectors: up to 4 m diameter
 - Industrial working conditions
 - Range of deformations: 1 μm 250 μm

LWIR DH well suited







Application in metrology for European Space Agency Cesa

M. Georges et al., Applied Optics **52**(1), A102-A116 (2013) J-F. Vandenrijt et al., Opt. Eng. **53**(11), 112309 (2014)



Application in metrology for European Space Agency Cesa









Application in metrology for European Space Agency Cesa



Measure during vacuum-cryogenic test:

- Deformation of each detector
- Deformation of ensemble
- Rigid body motions of each detector
- Large rigid body motion of ensemble

In the range of LWIR DHI



J-F. Vandenrijt et al., Appl. Opt. 55(12), 121723 (2016)

Motivation:

- Application in defect detection (NDI) in materials transparent ٠
- Digital holography allows reconstruction at different depths numerically based on single shot





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(Rohacell)

Motivation:

- Application in defect detection (NDI) in plastics/composites
- Digital holography allows reconstruction at different depths numerically based on single shot



(Without lens...)

P=500 mW @ λ=118.8 μm (2.5 THz)

- Validity of paraxial approximation at FIR
 - Object must be very close to the sensor (a few cm)
 - Reconstruction by S-FFT feasible but lateral resolution very poor
- Solution: Use rigorous Angular Spectrum Method (ASM)
 - Size of reconstructed object = size of detector
 - Lateral resolution proportional to distance object-sensor \boldsymbol{d}

Set-up:







Improve resolution

- Decrease distance d
- Problem : occlusion of reference beam by object
- Large angles : difficult and occlusion by camera frame





Image degradation !

Recorded holograms with occlusion

Use of phase retrieval to recover image and improve resolution



Use of phase retrieval to recover image and improve resolution



Experimental







 $\rho_{\rm V} = 152.9 \,\mu{\rm m}$

Intensity in-line

- Many composite materials are not transparent enough at FIR
- Move to sub-THz (1 mm wavelength)
 - Other detectors/sources
 - No cameras Single point detectors or line sensors (FET) •
- Transparency test with true aerospace materials



Focal plane Imaging Pitch 0,5mm

Front (source side)

Back



Collaboration with CENTERA Poland

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Scanning hologram with single point detectors

Digital holography validation

Amplitude object: metallic cross Phase object: plastic stick



Without object

140 160 180

20

With object



Source 140 GHz

- 100 mm*100 mm hologram
- pitch: 0,5mm
- 2 hours scan

Object amplitude

Phase difference

Conclusion – Discussion

- LWIR digital holography
 - Large deformation of space structures in industrial environment
 - Large objects
- THz digital holography
 - FIR: development of techniques (improvement of resolution)
 - Sub-THz: first steps for composites NDI
 - In future: line-scanning
- Improvement of DH
 - Use of DH principle and all associated post-processing
 - From FIR to sub-THz
 - State-of-art in lensless imaging techniques
 - EMPA, Switzerland
 - Beijing Univ. Technology, China
 - CSL, Belgium

"THz coherent lensless imaging techniques – A Review" L. Valzania, Y. Zhao, L. Rong, D. Wang, M. Georges, E. Hack, P. Zolliker (submitted)

Phase retrieval Numerical auto-focusing Synthetic aperture Compressed sensing

Further readings



MENTATION AND MEASUREMENT SERIE



"Long-wave Infrared Digital Holography"

in New Techniques in Digital Holography Wiley-ISTE, 2014



"Holographic interferometry: From History to Modern Applications"

in Optical Holography. Materials, Theory and Applications Elsevier, 2019 (in press)



Announcement

- NANO- AND QUANTUM SCIENCES PE101 Metamaterials (MacDonald, Staude, Zayats).....5 PE102 Nanophotonics (Andrews, Bain, Kauranen, Nunzi)6 PE103 Advances in Ultrafast Condensed Phase Physics (Haacke, Sharma, Yakovlev)......7 PE104 Quantum Technologies
- (Diamanti, Ducci, Treps, Whitloch PE105 Terahertz Photonics (Jarrahi, Preu.
- Turchinovich) OPTICAL IMAGING AND SENSING

PE106 3D Printed Optics and Additive

Photonic Manufacturing (Herkommer, von Freymann, Flury) 10

- PE107 Digital Optics for Immersive Displays (DOID20) (Kress Peroz)
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- Applications (Schelkens, Kozacki) 16 PE111 Optical Sensing and Detection (Berghmans, Mignani, O'Keefe). 18

LASERS AND NONLINEAR OPTICS

- PE112 Micro-Structured and Specialty Optical Fibres (Kalli, Peterka, Bunge) . . 20
- PE113 Semiconductor Lasers and Laser Dynamics (Sciamanna, Michalzik,
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- (Ferrari, Mackenzie, Taccheo). 22 PE115 Nonlinear Optics and its Applications (Broderick, Dudley, Peacock)......24

PE116	Blomedical Spectroscopy, Microscopy, and imaging (Popp, Gergely)
E117	Neurophotonics (Pavone)
PE118	Blophotonics in Point-of-Care (Canva, Giannetti, Altug, Moreau)27
PE119	Clinical Biophotonics (Elson, Gioux, Pogue)
E120	Tissue Optics and Photonics

APPLICATIONS OF PHOTONIC

TECHNOLOGY

- PE121 Silicon Photonics: from Fundamental Research to Manufacturing
- PE122 Organic Electronics and Photonics: Fundamentals and Devices
- PE123 Photonics for Solar Energy Systems (Wehrspohn, Sprafke)..... 32
- PE124 Photosensitive Materials and their Applications (McLeod, Pascual Villalobos,

WORKSHOPS ON EMERGING TOPICS

- WS201 Neuro-Inspired Photonic Computing (Sciamanna, Bienstman)......34
- WS202 Synthesis of Photonics and Plasmonics at the Mesoscale
- WS203 Light Shaping Focus Session
- WS204 6th annual Sino-French "Photonics and Optoelectronics" PHOTONET International Research Network Workshop (Blondel, Gralak



Thanks for your attention !

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Strasbourg (FR), March 29-April 2, 2020

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Submit abstracts by 25 September 2019

BIOPHOTONICS P